

# DTS8765 Dynamic Parameter Power Semiconductor Test System



## Features – preliminary –

- Currents up to 10.000 A
- Voltages up to 1.500 V
- Pulse length down to 10  $\mu$ s
- Very low parasitic inductance down to 15 nH
- Accuracy down to pA-resolution
- Optimized for high speed production testing
- Test-System comes with ready-to-run test sequencing software
- High speed instrument interfacing
- Reduced thermal effects on DUT and cabling
- Very low noise level due to isolated measurement technology along with high-side measurements
- Zero-Leakage-Current technology and highest precision due to complete guarding

Datasheet coming soon...

Visit the product page:  
[www.vxinstruments.com/DTS8765](http://www.vxinstruments.com/DTS8765)

